

Resource Summary Report

Generated by [RRID](#) on Aug 11, 2026

JEOL: JCM-6000 Benchtop Scanning Electron Microscope

RRID:SCR_027403

Type: Tool

Proper Citation

JEOL: JCM-6000 Benchtop Scanning Electron Microscope (RRID:SCR_027403)

Resource Information

URL: <https://www.jeol.com/products/scientific/sem/JCM-6000.php>

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Description: Compact Benchtop Scanning Electron Microscope. Intuitive operation is achieved via touch panel and new operation screens. The high or low vacuum mode is included in the standard configuration, and EDS can be installed, offering truly multi-functional benchtop SEM.

Synonyms: Jeol JCM-6000

Resource Type: instrument resource

Keywords: Jeol, benchtop, scanning electron microscope, microscope

Availability: Restricted

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_027403.pdf

Resource Name: JEOL: JCM-6000 Benchtop Scanning Electron Microscope

Resource ID: SCR_027403

Alternate IDs: Model_Number_Jeol_JCM-6000

Record Creation Time: 20250906T054930+0000

Record Last Update: 20260808T190801+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JCM-6000 Benchtop Scanning Electron Microscope.

No alerts have been found for JEOL: JCM-6000 Benchtop Scanning Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.